

Notice of References Cited	Application/Control No. 10/021,224	Applicant(s)/Patent Under Reexamination AN CHANG ET AL.	
	Examiner Brian J. Detwiler	Art Unit 2173	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,621,509	09-2003	Eiref et al.	345/836
	B	US-6,608,640	08-2003	Nagahara et al.	345/848
	C	US-6,295,062	09-2001	Tada et al.	345/835
	D	US-6,097,393	08-2000	Prouty et al.	345/419
	E	US-6,054,989	04-2000	Robertson et al.	345/848
	F	US-5,838,317	11-1998	Bolnick et al.	345/764
	G	US-5,835,094	11-1998	Ermel et al.	345/848
	H	US-5,671,381	09-1997	Strasnick et al.	345/848
	I	US-2002/0163546	11-2002	Gallo, Anthony Carmen	345/848
	J	US-2002/0105533	08-2002	Cristo, Constantine Gus	345/706
	K	US-2002/0075312	06-2002	Amadio et al.	345/764
	L	US-2002/0054163	05-2002	Yamada et al.	345/848
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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